A 5-DAY LECTURE SERIES for users with experience in ion and electron microscopy, on the fundamentals of focused ion beam (FIB), scanning electron microscopy (SEM), energy dispersive X-ray spectroscopy (EDS), 3D FIB characterization, correlative workflows, electron backscattered diffraction (EBSD), transmission kikuchi diffraction (TKD), environmental SEM (ESEM), and atom probe tomography (APT). The aim is to provide attendees with a broad range of lectures from experts in FIB, SEM, and APT from around the world. The lecture series is based on the CCEM Summer School on Advanced Microscopy with content tailored to an online forum and for a mix of intermediate to advanced users.

Workshop is a FREE Hosted by the CCEM

- REGISTER at ccem.mcmaster.ca/outreach-courses-and-events/

**TIME (EASTERN) MONDAY JUNE 7, 2021**

10 – 10:50  Raynald Gauvin (McGill): Theory and Advances in SEM
11 – 11:50  Nestor Zaluzec (ANL): Fundamentals of XEDS in the SEM

**TUESDAY JUNE 8, 2021**

10 – 10:50  Marco Cantoni (EPFL): 3D Characterization with FIB
11 – 11:50  Keana Scott (NIST): Advanced FIB applications
12 – 12:50  Nicolas Piché (ORS): Image Processing for 3D FIB Tomography

**WEDNESDAY JUNE 9, 2021**

16 – 16:50  Annalena Wolff (QUT): Helium Ion Microscopy - Advanced Topics and Applications
17 – 17:50  Alex de Marco (Monash): Theory and Advances to CLEM

**THURSDAY JUNE 10, 2021**

10 – 10:50  Joseph Michael (SNL): Introduction to EBSD: Current Issues in Data Presentation
11 – 11:50  Patrick Trimby (Oxford Instruments): Theory and Advances in TKD

**FRIDAY JUNE 11, 2021**

10 – 10:50  Baptiste Gault (MPIE): Theory and Advances in APT
11 – 11:50  Konrad Rykaczewski (ASU): Theory and Advances in ESEM and Cryo-Liquids
12 – 12:50  Baishakhi Mazumder (UB): Advanced APT Applications